

Title (en)
Sample preparation stage

Title (de)
Probenvorbereitungshalter

Title (fr)
Étage de préparation d'échantillon

Publication
EP 2765591 B1 20160713 (EN)

Application
EP 13154537 A 20130208

Priority
EP 13154537 A 20130208

Abstract (en)
[origin: US8754384B1] Described is a system and method for in situ sample preparation and imaging. The system includes a multi-axis stage 100 having a bulk stage 110 and a grid stage 150 with various degrees of freedom to allow for sample preparation. In some embodiments, a focused ion beam system is used to prepare a lamella on the bulk stage 110. The lamella can then be transferred to the grid stage 150 from the bulk stage 110 without needing to move the multi-axis stage 100 from the focused ion beam system.

IPC 8 full level
G01N 1/06 (2006.01); **H01J 37/20** (2006.01); **H01J 37/305** (2006.01)

CPC (source: EP US)
H01J 37/20 (2013.01 - EP US); **H01J 37/3056** (2013.01 - EP US); **G01N 2001/2873** (2013.01 - EP US); **H01J 2237/2001** (2013.01 - EP US); **H01J 2237/202** (2013.01 - EP US); **H01J 2237/204** (2013.01 - EP US); **H01J 2237/206** (2013.01 - EP US); **H01J 2237/208** (2013.01 - EP US); **H01J 2237/31745** (2013.01 - EP US)

Cited by
EP4068334A3; EP3166126A1

Designated contracting state (EPC)
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US 8754384 B1 20140617; CN 103983485 A 20140813; CN 103983485 B 20170630; EP 2765591 A1 20140813; EP 2765591 B1 20160713; JP 2014153362 A 20140825; JP 6418747 B2 20181107

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